

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/707,877	LONG, J. WAYNE	
Examiner <i>K. A.</i> Kamran Afshar, 571-272-7796		Art Unit 2681	Page 1 of 1	

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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